Application/Control No. Applicant(s)/Patent Under Reexamination 09/626,347 DE HEER ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Alford W. Kindred 2163 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY 11-2000 Α US-6,151,582 Huang et al. 705/8 US-В US-С D US-Ε US-F US-US-G US-Н US-1 J US-Κ US-US-L US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

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